## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10620376	HAYASHI ET AL.
Examiner	Art Unit
Hodge, Robert	1795

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted Jonathan Crepeau Re Previous Grounds of Rejection and New Grounds of Rejection and Motivation	10/24/07	RWH		
See attached East Search History	10/24/07	RWH		

INTERFERENCE SEARCH						
Class	Subclass	Date	Examine			

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